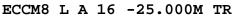
ECCM8LA16-25.000M TR



L Packaging Options Tape & Reel





Mode of Operation

Nominal Frequency 25.000MHz Load Capacitance 16pF Parallel Resonant

AT-Cut Fundamental

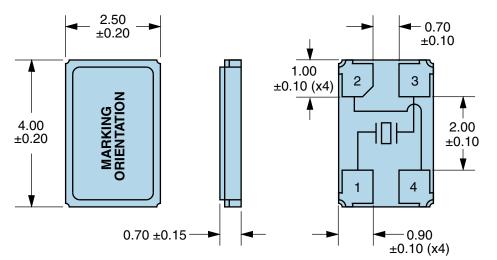
ELECTRICAL SPECIFICATIONS

| Nominal Frequency | 25.000MHz |
|-------------------------------|--|
| Frequency Tolerance/Stability | ±15ppm at 25°C, ±20ppm over -20°C to +70°C |
| Aging at 25°C | ±3ppm/Year Maximum |
| Load Capacitance | 16pF Parallel Resonant |
| Shunt Capacitance (C0) | 5pF Maximum |
| Equivalent Series Resistance | 60 Ohms Maximum |
| Mode of Operation | AT-Cut Fundamental |
| Drive Level | 100µWatts Maximum, 10µWatts Correlation |
| Crystal Cut | AT-Cut |
| Spurious Response | >3dB from Fo to Fo+5000ppm |
| Drive Level Dependancy (DLD2) | 20% of Maximum ESR Limit (from 1µWatt to 100µWatt) |
| Insulation Resistance | 500 Megaohms Minimum at 100Vdc |

ENVIRONMENTAL & MECHANICAL SPECIFICATIONS

| ESD Susceptibility | MIL-STD-883, Method 3015, Class 1, HBM: 1500V |
|------------------------------|---|
| Fine Leak Test | MIL-STD-883, Method 1014, Condition A |
| Flammability | UL94-V0 |
| Gross Leak Test | MIL-STD-883, Method 1014, Condition C |
| Mechanical Shock | MIL-STD-883, Method 2002, Condition B |
| Moisture Resistance | MIL-STD-883, Method 1004 |
| Moisture Sensitivity | J-STD-020, MSL 1 |
| Resistance to Soldering Heat | MIL-STD-202, Method 210, Condition K |
| Resistance to Solvents | MIL-STD-202, Method 215 |
| Solderability | MIL-STD-883, Method 2003 |
| Temperature Cycling | MIL-STD-883, Method 1010, Condition B |
| Vibration | MIL-STD-883, Method 2007, Condition A |

MECHANICAL DIMENSIONS (all dimensions in millimeters)



| PIN | CONNECTION |
|-----------|--------------------------------|
| 1 | Crystal |
| 2 | Cover/Ground |
| 3 | Crystal |
| 4 | Cover/Ground |
| | |
| LINE | MARKING |
| LINE 1 | MARKING E25.0 E=Ecliptek |